

Search Notes

Application/Control No.

10/814,266

Examiner

Thien F. Tran

Applicant(s)/Patent under
Reexamination

KATSUMATA ET AL.

Art Unit

2811

SEARCHED

Class	Subclass	Date	Examiner
257	336, 344	1/19/2005	TT
257	408, 900	1/19/2005	TT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR